

Search Notes

Application/Control No.

10/605,203

Examiner

Ernest F. Karlsen

Applicant(s)/Patent under
Reexamination

FLEISCHMAN, THOMAS J.

Art Unit

2829

SEARCHED

Class	Subclass	Date	Examiner
324	158.1 754 765	2/1/2005	E.F.K.
714	700 724	2/1/2005	E.F.K.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
324	158.1 765	2/5/2005	E.F.K.

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
time same delay same errors and test and semiconductor		
time adj delay adj error\$	2/1/2005	E.F.K.
calibrat\$ same (time or timing) same test		